



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Shunpei YAMAZAKI et al.      Art Unit : 2871  
Serial No. : 09/809,646      Examiner : Unknown  
Filed : March 16, 2001  
Title : SEMICONDUCTOR DISPLAY DEVICE AND MANUFACTURING METHOD  
THEREOF

Commissioner for Patents  
Washington, D.C. 20231

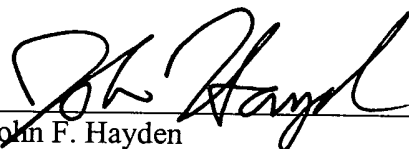
**INFORMATION DISCLOSURE STATEMENT**

Applicants submit the references listed on the attached form PTO-1449, copies of which are enclosed. A copy of a communication from a foreign patent office in a counterpart application is also enclosed.

This statement is being filed before issuance of a first Office action on the merits. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: June 12, 2002

  
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John F. Hayden  
Reg. No. 37,640

Fish & Richardson P.C.  
1425 K Street, N.W.  
11th Floor  
Washington, DC 20005-3500  
Telephone: (202) 783-5070  
Facsimile: (202) 783-2331

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Substitute Form PTO-1449 (Modified)  <b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary)  (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office		Attorney's Docket No. 12732-021001	Application No. 09/809,646
	Applicant Shunpei Yamazaki et al.			
	Filing Date March 16, 2001		Group Art Unit 2871	

## U.S. Patent Documents

Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	4,394,182	07/19/1983	Maddox, III			10/14/1981
	AB	5,272,100	12/21/1993	Satoh et al.			12/21/1993
	AC	5,750,430	05/12/1998	Son			08/23/1996
	AD	5,828,103	10/27/1998	Hsu			12/26/1995
	AE	5,986,305	11/16/1999	Wu			03/30/1998
	AF	6,031,290	02/29/2000	Miyazaki et al.			03/13/1998
	AG	6,369,410	04/09/2000	Yamazaki et al.			12/15/1998
	AH						

## Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AI	6-148685	05/27/1994	Japan			Abs	
	AJ	7-235680	09/05/1995	Japan			Abs	
	AK	8-274336	10/18/1996	Japan			Abs	
	AL	10-233511	09/02/1998	Japan			Abs	
	AM	11-261075	09/24/1999	Japan			Abs	
	AN	2001-210832	08/03/2001	Japan			Abs	
	AO	EP 1 001 467 A2	05/17/2000	Europe				
	AP	EP 1 003 223 A2	05/24/2000	Europe				

## Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AQ	
	AR	
	AS	
	AT	

Examiner Signature

Date Considered

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.